

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Mehdi Vaez-Iravani et al.

Title: Improved Sample Inspection System

I.A. Application No.:	PCT/US98/19564	I.A. Filing Date:	09/18/1998
Application No.:	10/070,079	Priority Date:	09/19/1997
Examiner:	Hoa Q. Pham	Group Art Unit:	2877
Docket No.:	TNCR.152US5	Conf. No.:	7208

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Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**INFORMATION DISCLOSURE STATEMENT**

Dear Sir:

Dear Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant(s) call(s) the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

Copies of the documents listed on the accompanying Form PTO-1449 are enclosed.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

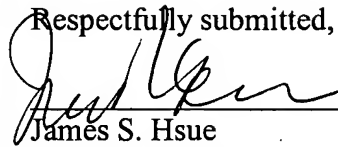
This information disclosure statement is submitted under 37 C.F.R. § 1.97(b) and consequently no fee should be required. The Commissioner is authorized, however, to charge

any fee that may be required, or to credit any overpayment, against Deposit Account No. 502664. This form is being submitted in duplicate.

EXPRESS MAIL NO.:

EV437667819US

Respectfully submitted,



James S. Hsue  
Reg. No. 29,545

8/23/04  
Date

U.S. Department of Commerce, Patent and Trademark	Atty. Docket No.	Application No.
INFORMATION DISCLOSURE STATEMENT BY APPLICANT	TNCR.152US5	10/070,079
	Applicant(s)	Conf. No.
(Use several sheets if necessary)	M. Vaez-Iravani et al.	7208
	Filing Date	Group
	January 9, 2004	2877

## U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	4,558,949	12/85	Uehara et al.			
	AB	4,893,932	1/1990	Knollenberg			
	AC	5,058,982	10/1991	Katzir			
	AD	5,389,794	2/14/1995	Allen et al.			
	AE	5,712,701	1/98	Dementi et al.			
	AF	5,929,983	7/99	Lu			
	AG	6,118,525	9/00	Fossey et al.			
	AH	6,169,601	1/01	Eremin et al.			

## U.S. Published Patent Application Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate

## Foreign Patent Documents

							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AI	WO97/33158	9/1997	International			X	
	AJ	EP0624787	11/1994	Europe			Abstract	
	AK	DE4123916	1/1992	German			Abstract	
	AL	WO97/12226	4/1997	International			X	

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AM	"Surface Inspection System for Estimation of Wafer," Y. Yatsugake et al., <i>Hitachi Electronics Engineering Technical Report</i> , Vol. 11, January 1996, pp. 21-26
AN	Figure, Hitachi Electronics Engineering Co., Ltd., presented by Etsuro Morita of Mitsubishi Materials Silicon Corp. in a presentation entitled "Exploration of COP and COP Defect Crystal Originated 'Particles'." at the 6 <sup>th</sup> International Workshop on 300 Millimeter Wafers on 12/5/1996 in Makuhari, Japan
AO	Partial European Search Report dated October 18, 2000

Examiner

Date Considered

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.

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## U.S. Patent Documents

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AP	4,589,773	5/86	Ido et al.			
	AQ	4,740,079	04/88	Koizumi et al.			
	AR	4,966,457	10/90	Hayano et al.			
	AS	5,125,741	6/92	Okada et al.			
	AT	5,189,481	2/93	Jann et al.			
	AU	5,245,403	9/93	Kato et al.			
	AV	5,465,145	11/95	Nakashige et al.			

## U.S. Published Patent Application Documents

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## Foreign Patent Documents

							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
	AW	WO96/15354	9/25/96	International			X	
	AX	WO97/04134	3/5/97	International			X	
	AY	WO99/14575	3/99	International			X	

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AZ	Search Report Corresponding to PCT Application No. PCT/US98/19564 issued by the International Patent Office on February 8, 1999.

Examiner

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